

Notice of References Cited	Application/Control No. 10/708,874		Applicant(s)/Patent Under Reexamination SHAN ET AL.	
	Examiner BRIAN P. YENKE		Art Unit 2622	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,414,719	07-2002	Parikh, Sandip	348/448
*	B	US-6,262,773	07-2001	Westerman, Larry Alan	348/448
*	C	US-5,990,978	11-1999	Kim et al.	348/663
*	D	US-5,365,281	11-1994	Ko et al.	348/700
*	E	US-5,339,113	08-1994	Iwasaki, Kiyoshi	348/604
*	F	US-7,046,299	05-2006	Lowe, Virgil L.	348/500
*	G	US-6,278,495	08-2001	Lowe et al.	348/665
*	H	US-6,300,985	10-2001	Lowe et al.	348/665
*	I	US-5,786,872	07-1998	Miyazaki et al.	348/669
*	J	US-5,430,500	07-1995	Hoshino et al.	348/701
*	K	US-5,285,266	02-1994	Jo, Hyun-Duk	348/665
*	L	US-6,400,762	06-2002	Takeshima, Masahiro	375/240.01
*	M	US-6,667,776	12-2003	Sumiyoshi et al.	348/669

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/708,874	Applicant(s)/Patent Under Reexamination SHAN ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2622	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,380,983	04-2002	Miyazaki et al.	348/554
*	B	US-6,122,767	09-2000	Ohara, Kazuhiro	714/822
*	C	US-5,603,013	02-1997	Ohara, Kazuhiro	703/23
*	D	US-6,914,638	07-2005	Tsui, Ernest T.	348/663
*	E	US-6,774,954	08-2004	Lee, Jooho	348/665
*	F	US-6,738,097	05-2004	Satoh, Yasunori	348/663
*	G	US-6,693,676	02-2004	Yamaguchi et al.	348/452
*	H	US-6,674,488	01-2004	Satoh, Yasunori	348/663
*	I	US-6,061,100	05-2000	Ward et al.	348/607
*	J	US-5,929,938	07-1999	Cho, Hyun-Duk	348/665
*	K	US-5,909,255	06-1999	Hatano, Takahisa	348/663
*	L	US-5,585,861	12-1996	Taniguchi et al.	348/669
*	M	US-5,502,509	03-1996	Kurashita et al.	348/669

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/708,874	Applicant(s)/Patent Under Reexamination SHAN ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2622	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,414,719	07-2002	Parikh, Sandip	348/448
*	B	US-6,262,773	07-2001	Westerman, Larry Alan	348/448
*	C	US-5,990,978	11-1999	Kim et al.	348/663
*	D	US-5,365,281	11-1994	Ko et al.	348/700
*	E	US-5,339,113	08-1994	Iwasaki, Kiyoshi	348/604
*	F	US-7,046,299	05-2006	Lowe, Virgil L.	348/500
*	G	US-6,278,495	08-2001	Lowe et al.	348/665
*	H	US-6,300,985	10-2001	Lowe et al.	348/665
*	I	US-5,786,872	07-1998	Miyazaki et al.	348/669
*	J	US-5,430,500	07-1995	Hoshino et al.	348/701
*	K	US-5,285,266	02-1994	Jo, Hyun-Duk	348/665
*	L	US-6,400,762	06-2002	Takeshima, Masahiro	375/240.01
*	M	US-6,667,776	12-2003	Sumiyoshi et al.	348/669

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.